N-channel TrenchMOS standard level FET Rev. 03 — 16 December 2010

Product data sheet

Product profile 1.

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Higher operating power due to low thermal resistance
- Low conduction losses due to low on-state resistance

1.3 Applications

- DC-to-DC converters
- General purpose switching
- Motor control circuits

- Suitable for high frequency applications due to fast switching characteristics
- Off-line switched-mode power supplies
- TV and computer monitor power supplies

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	200	V
I _D	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V}$	-	-	8.7	А
P _{tot}	total power dissipation	T _{mb} = 25 °C	-	-	88	W
Static cha	racteristics					
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 4.5 A; T _j = 25 °C	-	300	400	mΩ
Dynamic characteristics						
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; \text{ I}_{D} = 9 \text{ A};$ $V_{DS} = 160 \text{ V}; \text{ T}_{j} = 25 \text{ °C}$	-	12	-	nC



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2. Pinning information

Table 2.	Pinning	j information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	D	drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S

SOT78 (TO-220AB)

3. Ordering information

Table 3.Ordering information

Type number	Package		
	Name	Description	Version
PHP9NQ20T	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78

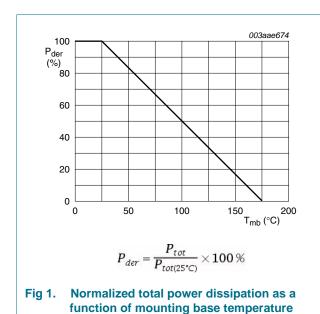
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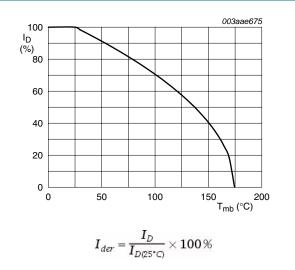
4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	200	V
V _{DGR}	drain-gate voltage	T _j ≥ 25 °C; T _j ≤ 175 °C; R _{GS} = 20 kΩ	-	200	V
V _{GS}	gate-source voltage		-30	30	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 100 °C	-	6.2	А
		V _{GS} = 10 V; T _{mb} = 25 °C	-	8.7	А
I _{DM}	peak drain current	pulsed; T _{mb} = 25 °C	-	35	А
P _{tot}	total power dissipation	T _{mb} = 25 °C	-	88	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-drai	n diode				
I _S	source current	T _{mb} = 25 °C	-	8.7	А
I _{SM}	peak source current	pulsed; T _{mb} = 25 °C	-	35	А
Avalanche I	uggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy		-	93	mJ
I _{AS}	non-repetitive avalanche current	$V_{sup} \le 25 \text{ V}; V_{GS} = 10 \text{ V}; T_{j(init)} = 25 \text{ °C};$ R _{GS} = 50 Ω ; unclamped	-	8.7	А





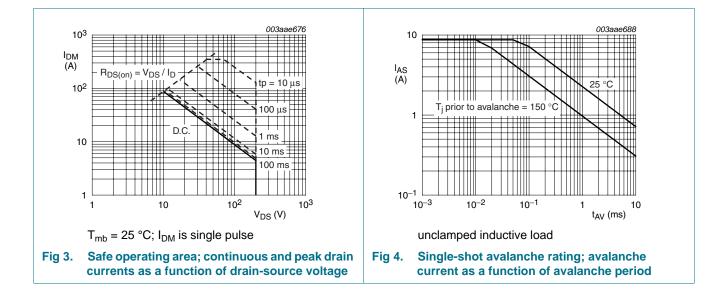


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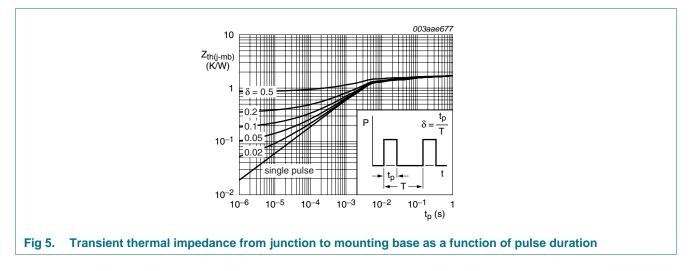


PHP9NQ20T Product data sheet

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5. Thermal characteristics

Table 5.	Thermal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base		-	-	1.7	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	in free air	-	60	-	K/W



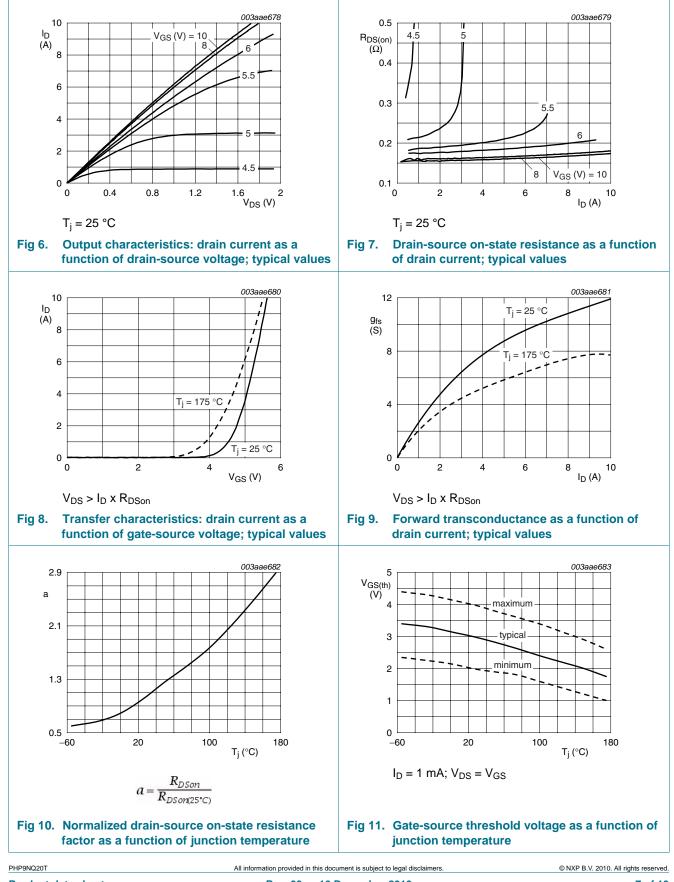
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6. Characteristics

<table-container>SymbolParameterConditionsMainFypeMaxMainStatic characterVariangesmain-source breakedown1=0 -0.25 mA; Vags = 0 V; T_i = .55 C1.68Valende1=0 -0.25 mA; Vags = 0 V; T_i = .55 C1.68<</table-container>	Table 6.	Characteristics					
$ \begin{split} & V_{(BR)DSS} & drain-source breakdown \\ voltage & l_{D} = 0.25 mA; V_{GS} = 0 V; T_{I} = 25 °C & 200 V \\ & I_{D} = 0.25 mA; V_{GS} = 0 V; T_{I} = .55 °C & 178 V \\ & I_{D} = 0.25 mA; V_{DS} = V_{GS}; T_{I} = 175 °C & 1 & V \\ & I_{D} = 1 mA; V_{DS} = V_{GS}; T_{I} = 175 °C & 1 & V \\ & I_{D} = 1 mA; V_{DS} = V_{GS}; T_{I} = 175 °C & 2 & 3 & 4 & V \\ & I_{D} = 1 mA; V_{DS} = V_{GS}; T_{I} = .55 °C & 2 & 3 & 4 & V \\ & I_{D} = 1 mA; V_{DS} = V_{GS}; T_{I} = .55 °C & . & & V \\ & I_{D} = 1 mA; V_{DS} = V_{GS}; T_{I} = .55 °C & . & & $	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Static cha	aracteristics					
$ V_{GS(th)} \qquad \begin{array}{ccccccccccccccccccccccccccccccccccc$	V _{(BR)DSS}		$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	200	-	-	V
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$		voltage	I_D = 0.25 mA; V_{GS} = 0 V; T_j = -55 °C	178	-	-	V
$ \frac{ l_{b} = 1 \text{ mA; } V_{DS} = V_{GS}; T_{j} = .55 \ ^{\circ}\text{C} & . & . & . & . & . & . & . & . & . & $	V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C}$	1	-	-	V
$ \begin{array}{llllllllllllllllllllllllllllllllllll$			$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	2	3	4	V
$ \begin{array}{ c c c c c c } \hline V_{DS} = 200 \ V; \ V_{SS} = 0 \ V; \ T_j = 25 \ ^{\circ}C & - & 10 & 100 & nA \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}C & - & 10 & 100 & nA \\ \hline V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}C & - & 10 & 100 & nA \\ \hline V_{GS} = 10 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ}C & - & 1.16 & \Omega \\ \hline V_{GS} = 10 \ V; \ V_{DS} = 10 \ V; \ V_{DS} = 10 \ V; \ T_j = 25 \ ^{\circ}C & - & 300 & 400 & m\Omega \\ \hline \hline Dramic \ characteristics & & & & & & & & & & \\ \hline Particle A \ Part$			$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C}$	-	-	6	V
	I _{DSS}	drain leakage current	V_{DS} = 200 V; V_{GS} = 0 V; T_j = 175 °C	-	-	500	μΑ
$ \frac{V_{GS} = -10 \ V; \ V_{DS} = 0 \ V; \ T_{j} = 25 \ ^{\circ}C \ - 10 \ 100 \ nA \ \Omega \ MB $			$V_{DS} = 200 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^\circ\text{C}$	-	0.05	10	μΑ
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	I _{GSS}	gate leakage current	V_{GS} = 10 V; V_{DS} = 0 V; T_j = 25 °C	-	10	100	nA
$\begin{array}{ c c c c c c c } \hline \mbox{resistance} & $V_{GS} = 10 \ V; \ I_D = 4.5 \ A; \ T_j = 25 \ ^{\circ} C & $300 \ \ \ 400 \ \ \ m\Omega \\ \hline \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$			V_{GS} = -10 V; V_{DS} = 0 V; T_j = 25 °C	-	10	100	nA
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	R_{DSon}		V_{GS} = 10 V; I _D = 4.5 A; T _j = 175 °C	-	-	1.16	Ω
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$		resistance	V_{GS} = 10 V; I_{D} = 4.5 A; T_{j} = 25 $^{\circ}C$	-	300	400	mΩ
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	Dynamic	characteristics					
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Q _{G(tot)}	total gate charge		-	24	-	nC
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Q_{GS}	gate-source charge	$l_j = 25 {}^{\circ}C$	-	4	-	nC
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	Q_{GD}	gate-drain charge		-	12	-	nC
CossOutput capacitance $r = 10^{-1}$ $r = 35^{-1}$ $p = 10^{-1}$ C_{rss} reverse transfer capacitance $V_{DS} = 100 \text{ V}; \text{ R}_L = 10 \Omega; \text{ V}_{GS} = 10 \text{ V};$ -54^{-1} $p = 10^{-1}$ $t_{d(off)}$ turn-on delay time $V_{DS} = 100 \text{ V}; \text{ R}_L = 10 \Omega; \text{ V}_{GS} = 10 \text{ V};$ -8^{-1} ns t_r rise time $R_{G(ext)} = 5.6 \Omega; \text{ T}_j = 25 \text{ °C}$ -19^{-1} ns $t_{d(off)}$ turn-off delay time -25^{-1} ns t_r fall time -15^{-1} ns g_{fs} transfer conductance $V_{DS} = 25 \text{ V}; \text{ I}_D = 4.5 \text{ A}; \text{ T}_j = 25 \text{ °C}$ 3.8^{-1} -8^{-1} L_D internal drain inductancefrom drain lead to centre of die ; -15^{-1} -8^{-1} -8^{-1} L_S internal source inductancefrom source lead to source bond pad ; -7^{-1} -8^{-1} -8^{-1} $Source-drain diode$ $I_S = 9 \text{ A}; \text{ V}_{GS} = 0 \text{ V}; \text{ T}_j = 25 \text{ °C}$ -8^{-1} -8^{-1} -8^{-1} V_{SD} source-drain voltage $I_S = 9 \text{ A}; \text{ dI}_S/\text{ dI}_$	C _{iss}	input capacitance		-	959	-	pF
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	Coss	output capacitance	$I_j = 25 {}^{\circ}C$	-	93	-	pF
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	C _{rss}	reverse transfer capacitance		-	54	-	pF
trinsertineinsertineinsertine $t_{d(off)}$ turn-off delay time-25-ns t_f fall time-15-ns g_{fs} transfer conductance $V_{DS} = 25 \text{ V}; I_D = 4.5 \text{ A}; T_j = 25 ^{\circ}\text{C}$ 3.86-S L_D internal drain inductancefrom drain lead to centre of die ; $T_j = 25 ^{\circ}\text{C}$ -4.5-nH L_S internal source inductancefrom source lead to source bond pad ; $T_j = 25 ^{\circ}\text{C}$ -3.5-nH L_S source-drain voltage $I_S = 9 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$ -0.851.2VV SDsource-drain voltage $I_S = 9 \text{ A}; dI_S/dt = -100 \text{ A}/\mus;$ -92-ns	t _{d(on)}	turn-on delay time		-	8	-	ns
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	t _r	rise time	$R_{G(ext)} = 5.6 \Omega; T_j = 25 C$	-	19	-	ns
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t _{d(off)}	turn-off delay time		-	25	-	ns
$ \begin{array}{c} L_{D} \\ L_{D} \\ L_{S} \end{array} \begin{array}{c} \text{internal drain inductance} \\ r_{j} = 25 \ ^{\circ}\text{C} \\ \hline \text{from tab to centre of die ;} \\ r_{j} = 25 \ ^{\circ}\text{C} \\ \hline \text{from tab to centre of die ;} \\ T_{j} = 25 \ ^{\circ}\text{C} \\ \hline \text{from tab to centre of die ;} \\ T_{j} = 25 \ ^{\circ}\text{C} \\ \hline \text{rom tab to centre of die ;} \\ T_{j} = 25 \ ^{\circ}\text{C} \\ \hline \text{rom source lead to source bond pad ;} \\ T_{j} = 25 \ ^{\circ}\text{C} \\ \hline \text{Source-drain diode} \\ \hline \\ V_{SD} \\ \hline \text{source-drain voltage} \\ I_{S} = 9 \ \text{A;} \ V_{GS} = 0 \ \text{V;} \ T_{j} = 25 \ ^{\circ}\text{C} \\ \hline \\ \text{source-drain voltage} \\ \hline \\ I_{S} = 9 \ \text{A;} \ \text{d}_{S} \text{d}_{S} = 0 \ \text{V;} \ T_{j} = 25 \ ^{\circ}\text{C} \\ \hline \\ \text{source-drain voltage} \\ \hline \\ \text{trr} \\ \hline \\ \hline \\ \text{reverse recovery time} \\ \hline \\ I_{S} = 9 \ \text{A;} \ \text{d}_{S} \text{d}_{S} = -100 \ \text{A} \text{/} \mu_{S}; \\ \hline \\ \text{source-drain voltage} \\ \hline \\ \ \ \text{source-drain voltage} \\ \hline \\ \ \ \text{source-drain voltage} \\ \hline \\ \ \ \ \text{source-drain voltage} \\ \hline \\ \hline \\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$	t _f	fall time		-	15	-	ns
$\begin{array}{c c c c c c c c c } T_{j} &= 25 \ ^{\circ}\text{C} & & & & & & & \\ \hline \text{from tab to centre of die ; } T_{j} &= 25 \ ^{\circ}\text{C} & & & & & & & \\ \hline \text{from tab to centre of die ; } T_{j} &= 25 \ ^{\circ}\text{C} & & & & & & \\ \hline \text{L}_{S} & & & & & & \\ \hline \text{internal source inductance} & & & & & & \\ \hline \text{from source lead to source bond pad ; } & & & & & & \\ \hline \text{Source-drain diode} & & & & & \\ \hline \text{V}_{SD} & & & & & & \\ \hline \text{source-drain voltage} & & I_{S} &= 9 \ \text{A}; \ \text{V}_{GS} &= 0 \ \text{V}; \ T_{j} &= 25 \ ^{\circ}\text{C} & & & & & \\ \hline \text{source-drain voltage} & & & & & \\ \hline \text{I}_{S} &= 9 \ \text{A}; \ \text{d}_{S}/\text{d}t &= -100 \ \text{A}/\mu\text{s}; & & & & & \\ \hline \text{everse recovery time} & & & & & \\ \hline \text{I}_{S} &= 9 \ \text{A}; \ \text{d}_{D}/\text{h}/\text{L} & & & & & & \\ \hline \text{from source lead to source lead to source bond pad ; } & & & & & \\ \hline \text{source-drain diode} & & & & & \\ \hline \text{source-drain voltage} & & & & & \\ \hline \text{I}_{S} &= 9 \ \text{A}; \ \text{d}_{S}/\text{d}t &= -100 \ \text{A}/\mu\text{s}; & & & & \\ \hline from source lead to sourc$	g fs	transfer conductance	V_{DS} = 25 V; I_D = 4.5 A; T_j = 25 °C	3.8	6	-	S
L_S internal source inductancefrom source lead to source bond pad ; $T_j = 25 \ ^\circ C$ 7.5-nHSource-drain diode V_{SD} source-drain voltage $I_S = 9 \ A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ C$ -0.851.2V t_{rr} reverse recovery time $I_S = 9 \ A; \ dI_S/dt = -100 \ A/\mu s;$ $V = -25 \ V = -25 \ ^\circ C$ -92-ns	L _D	internal drain inductance		-	4.5	-	nH
$T_{j} = 25 \text{ °C}$ Source-drain diode $V_{SD} \qquad \text{source-drain voltage} \qquad I_{S} = 9 \text{ A}; V_{GS} = 0 \text{ V}; T_{j} = 25 \text{ °C} \qquad - \qquad 0.85 \qquad 1.2 \text{V}$ $t_{rr} \qquad \text{reverse recovery time} \qquad I_{S} = 9 \text{ A}; dI_{S}/dt = -100 \text{ A}/\mu s; \qquad - \qquad 92 - \qquad \text{ns}$			from tab to centre of die ; $T_j = 25 \text{ °C}$	-	3.5	-	nH
V_{SD} source-drain voltage $I_S = 9 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$ -0.851.2V t_{rr} reverse recovery time $I_S = 9 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s};$ -92-ns	L _S	internal source inductance		-	7.5	-	nH
t _{rr} reverse recovery time $I_S = 9 \text{ A}; dI_S/dt = -100 \text{ A}/\mu s;$ - 92 - ns	Source-d	rain diode					
	V_{SD}	source-drain voltage	$I_S = 9 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.85	1.2	V
Q_r recovered charge $V_{GS} = -10 V; V_{DS} = 25 V; T_j = 25 °C - 0.5 - \mu C$	t _{rr}	reverse recovery time		-	92	-	ns
	Qr	recovered charge	V _{GS} = -10 V; V _{DS} = 25 V; T _j = 25 °C	-	0.5	-	μC

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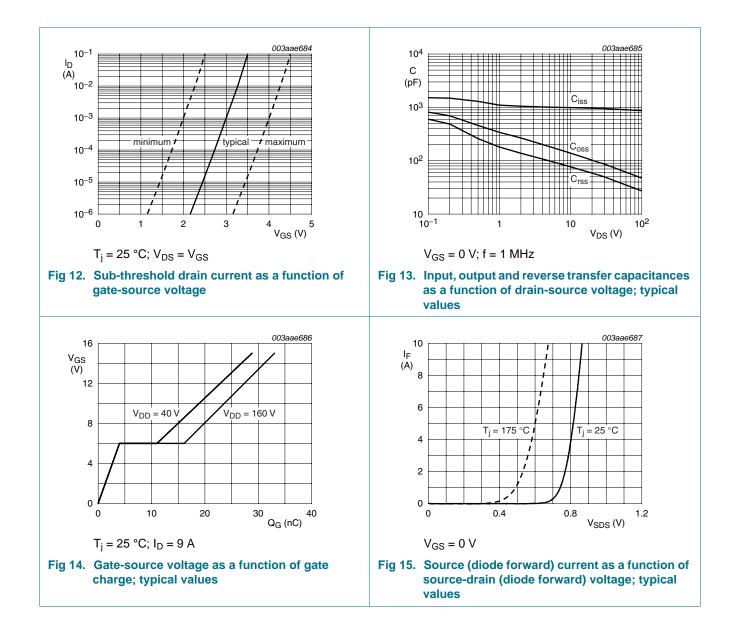
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Package outline 7.

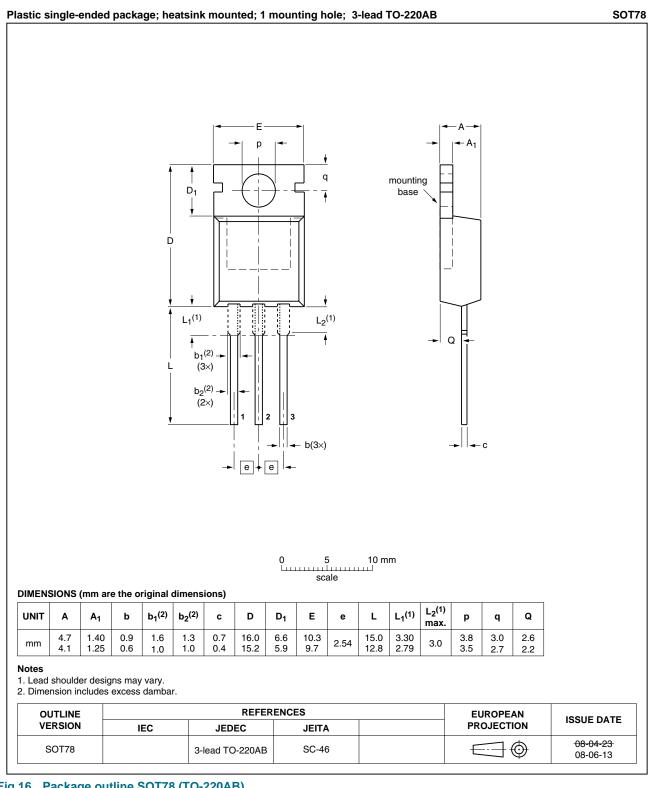


Fig 16. Package outline SOT78 (TO-220AB)

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PHP9NQ20T

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8. Revision history

Table 7.Revision history					
Document ID	Release date	Data sheet status	Change notice	Supersedes	
PHP9NQ20T v.3	20101216	Product data sheet	-	PHB_PHD_PHP9NQ20T v.2	
Modifications:	 The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. 				
	 Legal texts 	have been adapted to the	new company nan	ne where appropriate.	
	 Type number 	er PHP9NQ20T separated	d from data sheet P	HB_PHD_PHP9NQ20T v.2.	
PHB_PHD_PHP9NQ20T v.2	20001001	Product specification	-	PHB_PHD_PHP9NQ20T v.1	

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9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <u>http://www.nxp.com</u>.

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N-channel TrenchMOS standard level FET

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